

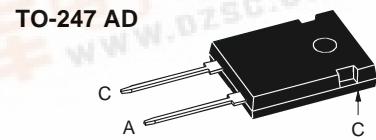


Fast Recovery Epitaxial Diode (FRED)

DSEI 120

$I_{FAVM} = 109 \text{ A}$
 $V_{RRM} = 1200 \text{ V}$
 $t_{rr} = 40 \text{ ns}$

V_{RSM}	V_{RRM}	Type
V	V	
1200	1200	DSEI 120-12A



A = Anode, C = Cathode

Symbol	Test Conditions		Maximum Ratings	
I_{FRMS}	$T_{VJ} = T_{VJM}$		100	A
I_{FAVM} ①	$T_c = 60^\circ\text{C}$; rectangular, $d = 0.5$		109	A
I_{FAV} ②	$T_c = 95^\circ\text{C}$; rectangular, $d = 0.5$		75	A
I_{FRM}	$t_p < 10 \mu\text{s}$; rep. rating, pulse width limited by T_{VJM}		tbd	A
I_{FSM}	$T_{VJ} = 45^\circ\text{C}$; $t = 10 \text{ ms}$ (50 Hz), sine		600	A
	$t = 8.3 \text{ ms}$ (60 Hz), sine		660	A
	$T_{VJ} = 150^\circ\text{C}$; $t = 10 \text{ ms}$ (50 Hz), sine		540	A
	$t = 8.3 \text{ ms}$ (60 Hz), sine		600	A
I^2t	$T_{VJ} = 45^\circ\text{C}$; $t = 10 \text{ ms}$ (50 Hz), sine		1800	A^2s
	$t = 8.3 \text{ ms}$ (60 Hz), sine		1800	A^2s
	$T_{VJ} = 150^\circ\text{C}$; $t = 10 \text{ ms}$ (50 Hz), sine		1450	A^2s
	$t = 8.3 \text{ ms}$ (60 Hz), sine		1500	A^2s
T_{VJ}			-40...+150	$^\circ\text{C}$
T_{VJM}			150	$^\circ\text{C}$
T_{stg}			-40...+150	$^\circ\text{C}$
P_{tot}	$T_c = 25^\circ\text{C}$		357	W
M_d	Mounting torque		0.8...1.2	Nm
Weight			6	g

Symbol	Test Conditions		Characteristic Values	
	typ.		max.	
I_R	$T_{VJ} = 25^\circ\text{C}$	$V_R = V_{RRM}$	3	mA
	$T_{VJ} = 25^\circ\text{C}$	$V_R = 0.8 \cdot V_{RRM}$	1.5	mA
	$T_{VJ} = 125^\circ\text{C}$	$V_R = 0.8 \cdot V_{RRM}$	20	mA
V_F	$I_F = 70 \text{ A}$	$T_{VJ} = 150^\circ\text{C}$	1.55	V
		$T_{VJ} = 25^\circ\text{C}$	1.8	V
V_{TO}	For power-loss calculations only		1.2	V
r_T	$T_{VJ} = T_{VJM}$		4.6	$\text{m}\Omega$
R_{thJC}			0.35	K/W
R_{thCK}			35	K/W
R_{thJA}			0.25	K/W
t_{rr}	$I_F = 1 \text{ A}$; $-\text{di}/\text{dt} = 200 \text{ A}/\mu\text{s}$	$V_R = 30 \text{ V}$; $T_{VJ} = 25^\circ\text{C}$	40	ns
I_{RM}	$V_R = 350 \text{ V}$; $I_F = 75 \text{ A}$; $-\text{di}_F/\text{dt} = 200 \text{ A}/\mu\text{s}$	$L \leq 0.05 \mu\text{H}$; $T_{VJ} = 100^\circ\text{C}$	25	30

① Chip capability, ② limited to 70 A by leads

Data according to IEC 60747

IXYS reserves the right to change limits, test conditions and dimensions

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Advantages

- High reliability circuit operation
- Low voltage peaks for reduced protection circuits
- Low noise switching
- Low losses
- Operating at lower temperature or space saving by reduced cooling

Dimensions

See DSEI 60-12 on page D5 - 27

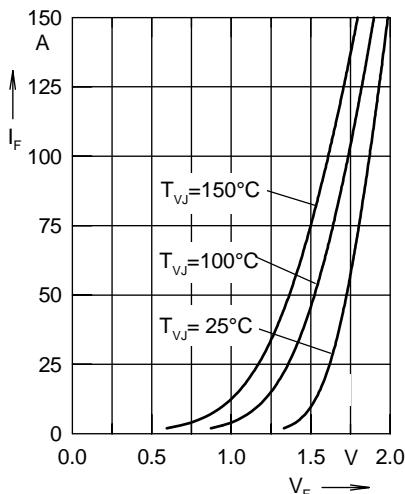


Fig. 1 Forward current I_F versus V_F

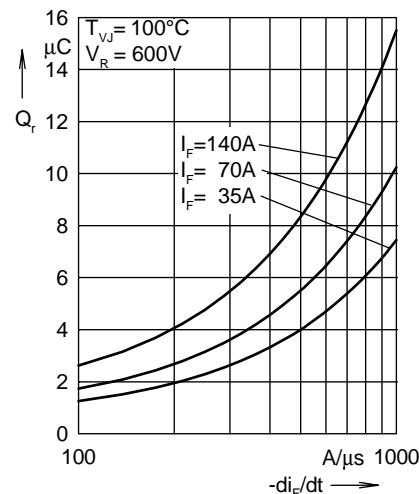


Fig. 2 Reverse recovery charge Q_r versus $-di_F/dt$

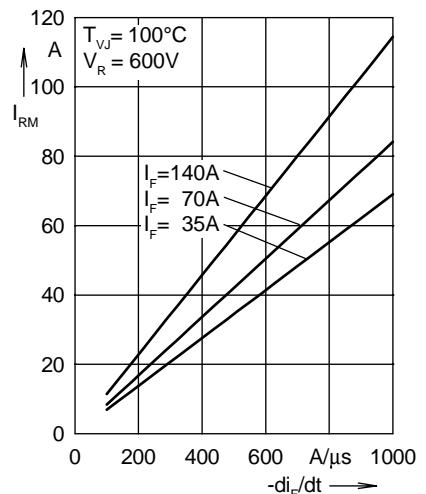


Fig. 3 Peak reverse current I_{RM} versus $-di_F/dt$

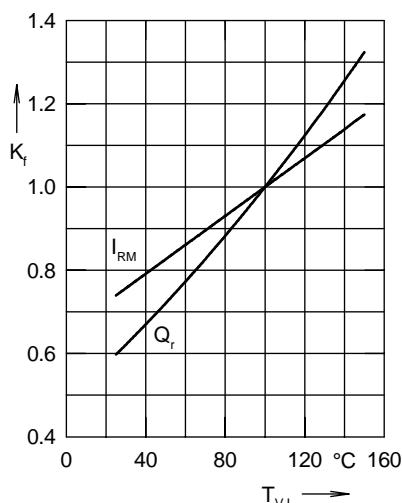


Fig. 4 Dynamic parameters Q_r , I_{RM} versus T_{VJ}

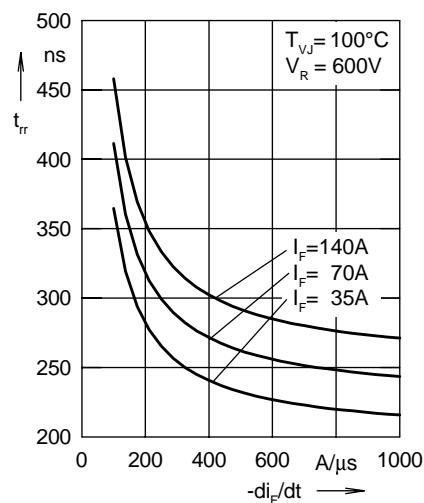


Fig. 5 Recovery time t_{rr} versus $-di_F/dt$

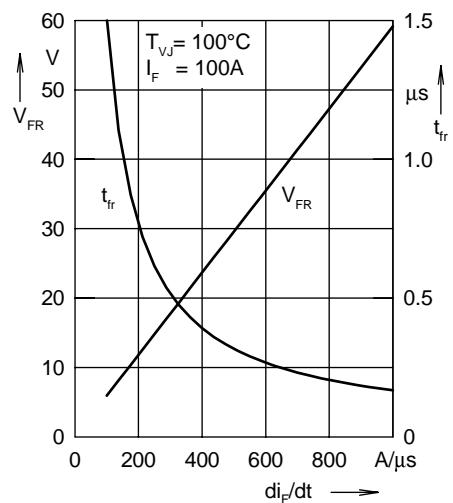


Fig. 6 Peak forward voltage V_{FR} and t_{rr} versus di_F/dt

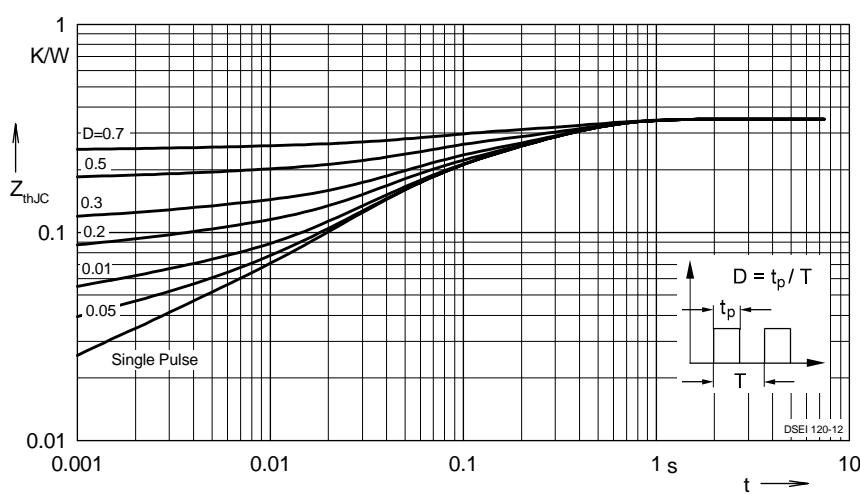


Fig. 7 Transient thermal resistance junction to case

Constants for Z_{thJC} calculation:

i	R_{thi} (K/W)	t_i (s)
1	0.017	0.00038
2	0.0184	0.0026
3	0.1296	0.0387
4	0.185	0.274